

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G9 SMD CRYSTAL
SPEC. NO. (P/N)	G93270001
CUSTOMER P/N	
ISSUE DATE	Jan.8,2014
VERSION	С

APPROVED	PREPARED	QA
Brenda	Clane	Bedryeri
APPROVED BY CUSTOMER:		AVL Status
Please return one copy		

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http://www.saronix-ecera.com.tw

*Pb-free

*RoHS Compliant

*HF-Halogen Free

*REACH Compliant



*** A company of PERICOM Semiconductor Corporation

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3-Oct-11

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
Α	Apr.18,2011			Initial Release	
В	Oct.3,2011			Changed Operating Temperature Range from -30~70C to -40~85C & Added Shunt Capacitance 7pF	
С	Jan.8,2014			Revised to RoHS Compliant	

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ELECTRICAL SPECIFICATIONS

SRe Part Number: G93270001

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25°C ± 5°C
Load Capacitance	CL	9	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ / Max.
Equivalent Series Resistance	ESR	90	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C2	Тур.
Operating Temperature Range	TR	-40~85	°C	
Shunt Capacitance	C0	7	pF	Max.
Storage Temperature Range		-55~125	°C	
Aging		± 3	ppm	Max 1st year
Insulation Resistance		500	МΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm
2	Shear test	A static load of 20N(2.04kgf) using a R0.5 scratch tool, shall be applied on the core of the component and in the direction of the arrow and held for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ
3	Core body strength	A static load of 10N(1.02kgf) using a R0.5 pressure rod shall be applied to the center in the direction of the arrow and held for 10 seconds.	
4	Vibration	Endurance conditioning by a frequency sweep shall be made. The entire frequency range, from 10Hz to 55Hz and return to 10Hz, shall be transversed in 1 minute. Amplitude (total excursion): 1.5mm, This motion shall be applied for a period of 2 hours in each of 3 mutually perpendicular axes (a total of 6 hours). For other procedures, refer to JIS C 60068-2-6.	
5	Shock	Peak acceleration: 9810m/s2 , Duration of the pulse: 1ms, Three successive shock shall be applied 3 times perpendicular axes. For other procedures, refer to JIS C 60068-2-27.	

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6	Cold	Quartz crystal units shall be stored in the -40±3°C atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1.			Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
7	Dry heat		re for 100 hours.	e stored in the 100±2 $^{\circ}$ C Other procedures conform	After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat	atmosphe	re with 90 to 95%	e stored in the 40±2°C b relative humidity for 1000 onform to JIS C 60068-2-3	
9	Change of temperature	Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025.		ige shown below. Other	100
		1 2 3 4	Temperatur -40±3°C Normal tempera 100±2°C Normal tempera	30min. hture Within 30 sec. 30min.	
10	Sealing	Both the test methods specified below shall be applied. Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure the leakage rate of helium gas.			 Without repetitive leaking bubbles from quartz crystal units. 1×10-9 Pa·m3/s or less
11	Aging	Quartz crystal units shall be stored in the 85±3°C atmosphere for 720±12 hours.			 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
12	Solder-ability		coated with flux h for 3.5±0.5 sec	shall be immersed in the onds.	Minimum 95% of immersed terminal shall be covered with new uniform solder.
			Items	Conditions	
		1	Solder	Sn-3.0Ag-0.5Cu	
			Flux	Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K	
		2		5902).	

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Reflow soldering method Resistance to soldering heat 温度プロファイル Temperature profile はんだ付け Soldering 260 Soldering temperature 220 徐冷(常温自然放置) 予熱 Slow cooling(Stored Pre-heating at room temperature) 160 Within 5s $90 \pm 10s$ • Frequency change: Within ±5ppm Peak temperature: 260±5° for within 5seconds. • Equivalent series resistance (E.S.R) Soldering temperature: 220°C or higher for 60±10 change: Within 10kΩ seconds. · After conditioning, quartz crystal units Pre-heating temperature: 160±10°C for 90±10 seconds shall be subjected to standard atmospheric Quartz crystal units which is put on PCB shall be conditions for 1 hour, and measured. through reflow soldering furnace twice with the condition · Without distinct deformation in shown above. appearance. Soldering iron method • Frequency change: Within ±5ppm Terminals shall be applied 400±10℃ soldering iron heat • Equivalent series resistance(E.S.R) for 3.5±0.5 seconds twice. change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. · Without distinct deformation in appearance. Solubility to Soak cleaning • Without mechanical damage such as breaks and satisfy sealing specification. resistance Quartz crystal units shall be soaked in isopropyl alcohol at normal temperature for 90 • Frequency change: Within ±5ppm seconds. • Equivalent series resistance(E.S.R) change: Within 5kΩ · Without distinct deformation in appearance.

· Marking shall be legible.

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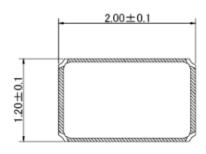
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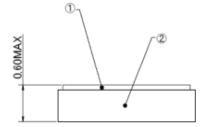
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Marking

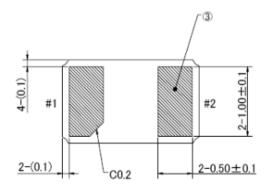


Dimensions (Units: mm)

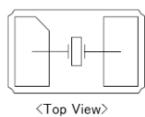




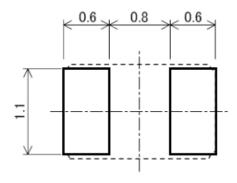




内部接続図 Internal connection



Land dimensions(unit: mm)

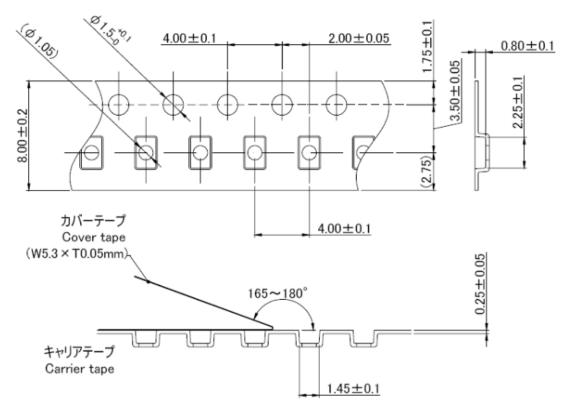


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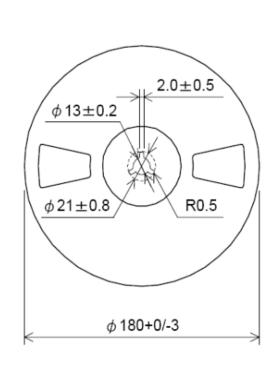
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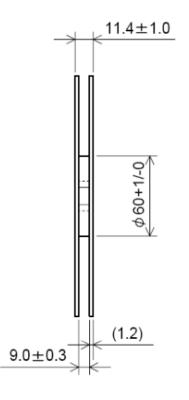
TAPING



REEL

Reel





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